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EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS		LING DATE
BU	AA	5,712,947	27Jan98	Oguro, et al.				
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Hu	АН	JP 5-165935	2Jul93	JAPAN		×		
DU.	Al	JP 5-81787	02Apr93	JAPAN		×		
111	AJ	JP 7-143429	02Jun95	JAPAN		×		
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the.	АМ	JP 11-215471	6Aug99	JAPAN (corresponding U.S. Patent no. 6,385,389 B1 Maruyama, et al.)				×
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